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For: DEFECT DETECTION SYSTEM AND METHOD

ABSTRACT OF DISCLOSURE

5 Detecting a defect in the sample is accomplished by photoacoustically exciting
acoustic longitudinal, surface Rayleigh, and shear waves at a first point on a near surface
of a sample; photoacoustically detecting acoustic waves at a second point spaced from the
excitation first point for intercepting shear waves reflected from the far surface of the
sample at approximately the angle of maximum shear wave propagation; and detecting
the energy level of the intercepted reflected shear waves representative of the flaw in the
10 sample.

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